

# Search Notes



Application/Control No.

10/817,196

Examiner

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Applicant(s)/Patent under  
Reexamination

JAIN ET AL.

Art Unit

2681

## SEARCHED

Class	Subclass	Date	Examiner
455	411	10/14/05	DN
370	332		
455	435.1		
340	5.21		
340	5.74		
380	242		
380	220	10/14/05	DN
Update search 04/13/06 DN			
455	410		
	412.1		
	432.1		
	432.2		
	432.3		
	433		
455	435.1	04/18/06	DN
	439		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
All above		04/18/06	DN

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East search	10/14/05	DN
Search note	10/14/05	DN
Update search	04/13/06	DN